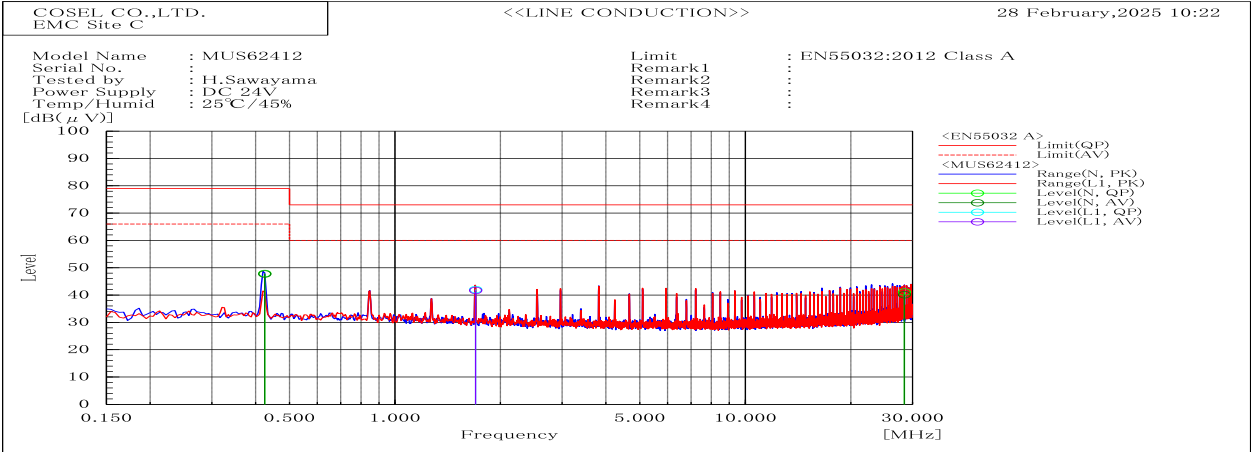
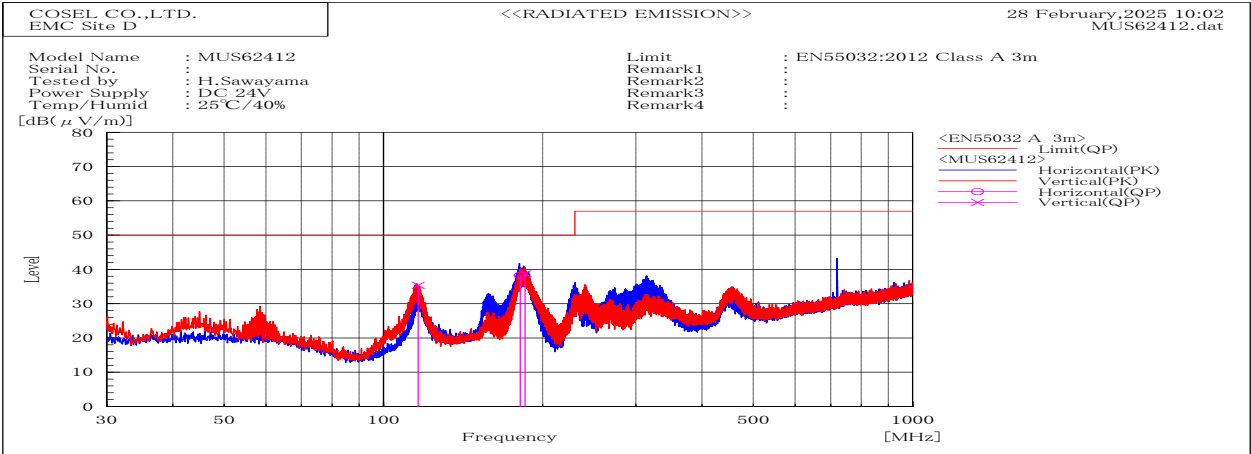


DATA SHEET		Date	28-Feb-25
Model	MUS62412	Temp.	25 degreeC
Test	EMI Line conduction & Radiated emission	Humid.	40 %RH
		Tested by	H.Sawayama



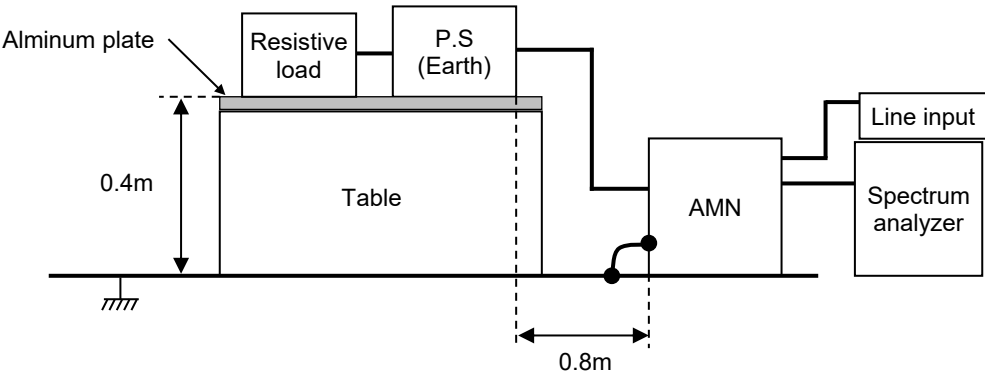
Frequency	Line	Level		Limit		Margin		Pass/Fail	Remark
MHz		dB(μV)		dB(μV)		dB			
		QP	AV	QP	AV	QP	AV		
1.698	L1	42	41.7	73	60	31	18.3	Pass	
0.425	N	47.9	47.7	79	66	31.1	18.3	Pass	
28.452	N	41.1	40.1	73	60	31.9	19.9	Pass	



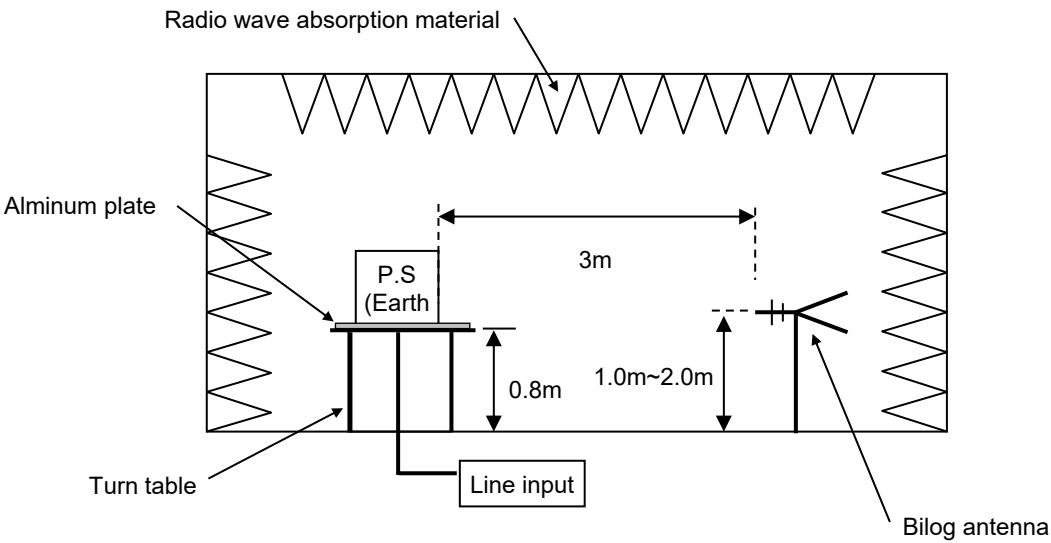
Frequency MHz	Polarization	Stability	Level	Limit	Margin	Pass/Fail	Height cm	Angle deg	Remark
			dB(uV/m) QP	dB(uV/m) QP	dB QP				
116.32	V	Stable	35.4	50	14.6	Pass	138.6	140.4	
185.12	V	Stable	38.7	50	11.3	Pass	100	37.8	
181.307	H	Stable	38.2	50	11.8	Pass	199.7	352.2	

DATA SHEET		Date	28-Feb-25
Model	Circuit used for measurement	Temp.	25 degreeC
Test	EMI Line conduction & Radiated emission	Humid.	40 %RH
		Tested by	H.Sawayama

1. Line conduction



2. Radiated emission



Conditions

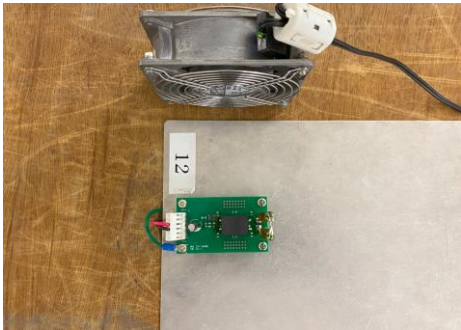
Test : EMI
Model Name: MUS6□□

○Photographs of Test Set-Up

LINE CONDUCTION



RADIATED EMISSION



○Testing circuitry

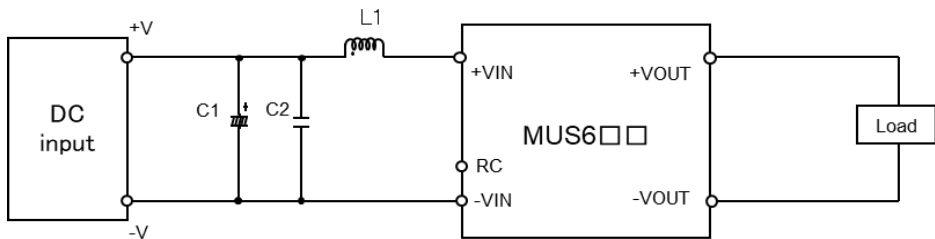


Fig.1 MUS6□□ Testing circuitry

C1 :	MUS605□	16V 220 μ F	Electric capacitor (UPWseries NICHICON)
	MUS612□	50V 100 μ F	Electric capacitor (UPWseries NICHICON)
	MUS624□	—	
	MUS648□	—	
C2 :	MUS605□	16V 22 μ F	Ceramic capacitor (GRM31CC71C226M MURATA MANUFACTURING)
	MUS612□	25V 10 μ F	Ceramic capacitor (CM316X7R106K25AT KYOCERA)
	MUS624□	50V 4.7 μ F	Ceramic capacitor (GRM31CR71H475K MURATA MANUFACTURING)
	MUS648□	100V 2.2 μ F	Ceramic capacitor (C3216X7S2A225KT TDK)
L1 :	MUS605□	6500mA 1.5 μ H	Inductor(LQH5BPN1R5N38 MURATA MANUFACTURING)
	MUS612□	5000mA 2.2 μ H	Inductor(LQH5BPN2R2N38 MURATA MANUFACTURING)
	MUS624□	2600mA 10 μ H	Inductor(LQH5BPN100M38 MURATA MANUFACTURING)
	MUS648□	1600mA 22 μ H	Inductor(LQH5BPN220M38 MURATA MANUFACTURING)